

# AP13P15GP-HF-VB Datasheet P-Channel 150 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)		
- 150	0.100 at V <sub>GS</sub> = - 10 V	- 20	13.7		
- 150	$0.120$ at $V_{GS} = -4.5$ V	- 18	13.7		

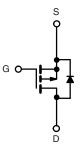
### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R<sub>q</sub> and UIS Tested
- Compliant to RoHS Directive 2002/95/EC



### **APPLICATIONS**

- · Power Switch
- DC/DC Converters



P-Channel MOSFET

TO-220A					
	(		)		
	G	D	S		
	Top	) Vi	ew		

ABSOLUTE MAXIMUM RATINGS	$T_C = 25  ^{\circ}C$ , unless other	rwise noted			
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V <sub>DS</sub>	- 150		
Gate-Source Voltage		V <sub>GS</sub>	± 20		
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	T <sub>C</sub> = 25 °C	1-	- 20	_	
Continuous Diam Current (1) = 130 C)	T <sub>C</sub> = 70 °C	I <sub>D</sub>	- 16		
Pulsed Drain Current	I <sub>DM</sub>	- 60	Α		
Avalanche Current		I <sub>AS</sub>	- 18		
Single Avalanche Energy <sup>a</sup> L = 0.1 mH		E <sub>AS</sub>	17.2	mJ	
	T <sub>C</sub> = 25 °C	Б	37.1 <sup>b</sup>	W	
Maximum Power Dissipation <sup>a</sup>	T <sub>A</sub> = 25 °C <sup>c</sup>	$ P_D$	2.5		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Limit	Unit	
Junction-to-Ambient (PCB Mount) <sup>c</sup>	R <sub>thJA</sub>	50	°C/W	
Junction-to-Case (Drain)	R <sub>thJC</sub>	3.9	C/VV	

### Notes:

- a. Duty cycle  $\leq$  1 %.
- b. See SOA curve for voltage derating.
- c. When Mounted on 1" square PCB (FR-4 material).



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 150			V	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 2.5	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 250	nA	
		V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V			- 1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 150 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			- 50	μΑ	
		V <sub>DS</sub> = - 150 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C			- 250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 20			Α	
	Б	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 5.0A		0.100		Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 4.0 A		0.120			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 5.0 A		12		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			1055		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = - 75 V, f = 1 MHz		65			
Reverse Transfer Capacitance	C <sub>rss</sub>	1 "		41			
·	Qg	V <sub>DS</sub> = -75V, V <sub>GS</sub> = -10 V, I <sub>D</sub> = -5.0 A		23.2	34.8	nC	
Total Gate Charge <sup>c</sup>				13.7	19.6		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	V <sub>DS</sub> = - 75 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 5.0 A		4.5			
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>	1		5.8			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	1.2	5.7	11.5	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			7	14		
Rise Time <sup>c</sup>	t <sub>r</sub>	V <sub>DD</sub> = - 75 V, R <sub>I</sub> = 17.2 Ω		12	18		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong -2.9 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		33	50	ns	
Fall Time <sup>c</sup>	t <sub>f</sub>	1		9	18	1	
Drain-Source Body Diode Ratings ar	nd Characteri	istics T <sub>C</sub> = 25 °C <sup>b</sup>					
Continuous Current	I <sub>S</sub>				- 8.8		
Pulsed Current	I <sub>SM</sub>				- 15	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = - 2.9 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			50	75	ns	
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = - 2.9 A, dl/dt = 100 A/μs		- 4	- 6	A	
Reverse Recovery Charge	Q <sub>rr</sub>			98	147	nC	

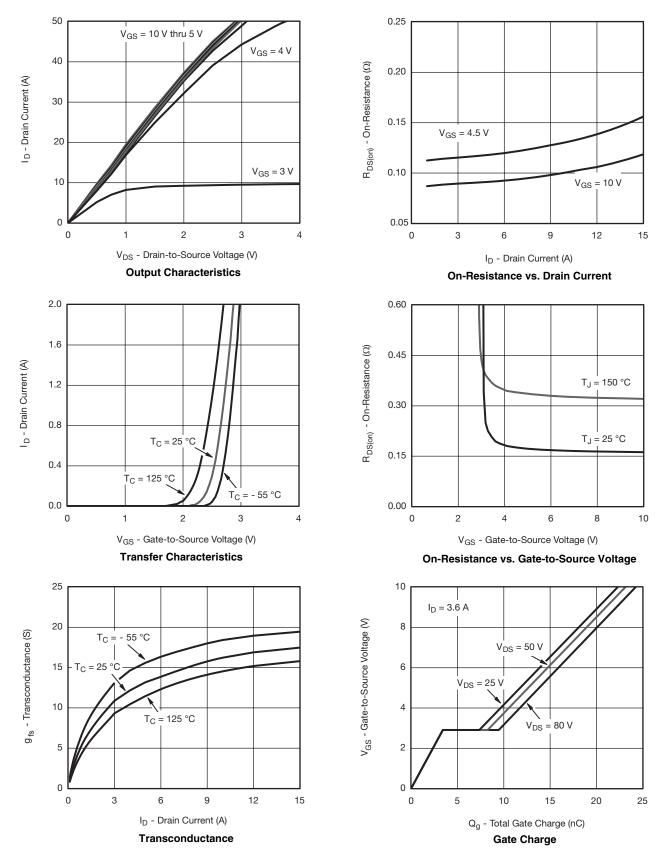
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

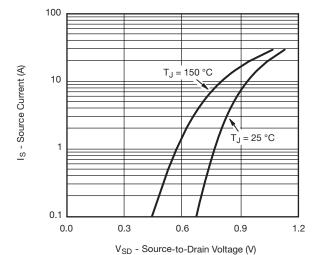


### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

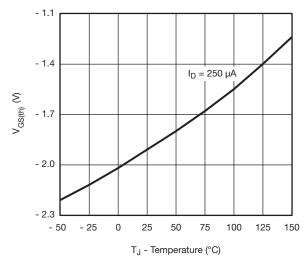




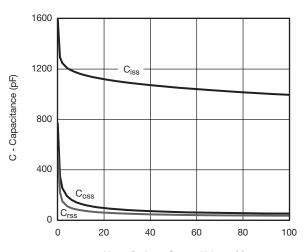
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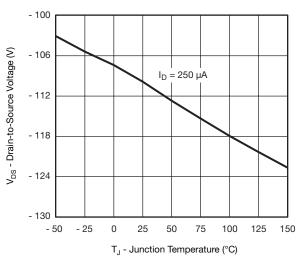
Source-Drain Diode Forward Voltage



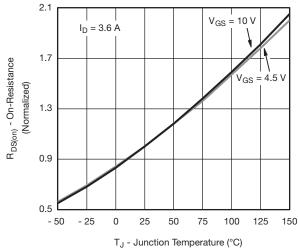
Threshold Voltage



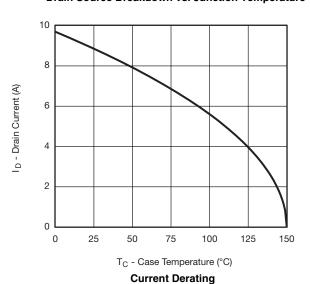
V<sub>DS</sub> - Drain-to-Source Voltage (V) Capacitance



Drain Source Breakdown vs. Junction Temperature

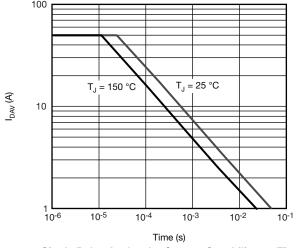


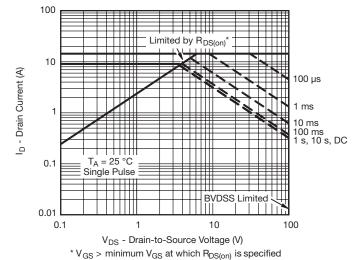
On-Resistance vs. Junction Temperature



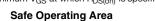


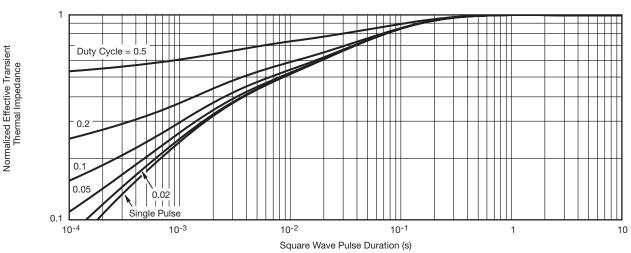
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Single Pulse Avalanche Current Capability vs. Time





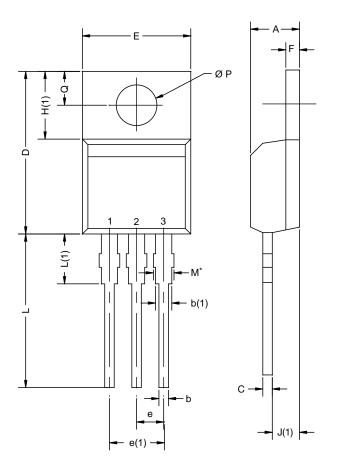
Normalized Thermal Transient Impedance, Junction-to-Case

服务热线:400-655-8788

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# **TO-220AB**



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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